

# Recent advances in Schottky barrier concepts

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Citation Report

#	ARTICLE	IF	CITATIONS
1	Scanning spreading resistance microscopy current transport studies on doped III-V semiconductors. Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena, 2002, 20, 1682.	1.6	36
2	X-ray photoemission determination of the Schottky barrier height of metal contacts on GaN and GaN. Journal of Applied Physics, 2002, 92, 6671-6678.	1.1	103
3	Charges and Dipoles at Semiconductor Interfaces. Materials Research Society Symposia Proceedings, 2002, 719, 1211.	0.1	0
4	The Cu/n-GaAs schottky barrier diodes prepared by anodization process. Journal of Electronic Materials, 2002, 31, 1362-1368.	1.0	27
5	The effects of the time-dependent and exposure time to air on Au/n-GaAs schottky barrier diodes. Applied Surface Science, 2002, 191, 188-195.	3.1	11
6	<sup>60</sup> Co gamma irradiation effects on n-GaN Schottky diodes. IEEE Transactions on Electron Devices, 2003, 50, 2326-2334.	1.6	96
7	Correlation between barrier heights and ideality factors of Cd/n-Si and Cd/p-Si Schottky barrier diodes. Solid State Communications, 2003, 125, 551-556.	0.9	35
8	Admittance spectroscopy of metal-semiconductor interfaces prepared by ionized cluster beam technique. Vacuum, 2003, 71, 123-128.	1.6	2
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10	Temperature dependence of characteristic parameters of the H-terminated Sn/p-Si(1 0 0) Schottky contacts. Applied Surface Science, 2003, 217, 250-260.	3.1	243
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16	Molecular modification of an ionic semiconductor-metal interface: ZnO/molecule/Au diodes. Applied Physics Letters, 2003, 82, 1051-1053.	1.5	61
17	Phase selective synthesis of gadolinium silicide films on Si(111) using an interfacial SiO <sub>2</sub> layer. Journal of Applied Physics, 2003, 94, 212-215.	1.1	8
18	Point defect distributions and their electrical effects on (Ba,Sr)TiO <sub>3</sub> /Pt thin films. Journal of Applied Physics, 2003, 94, 1926-1933.	1.1	13

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21	The barrier height inhomogeneity in identically prepared Pb/p-type Si Schottky barrier diodes. <i>Semiconductor Science and Technology</i> , 2003, 18, 642-646.	1.0	27
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